UCLouvain

2019

## Surface Analysis

In view of the health context linked to the spread of the coronavirus, the methods of organisation and evaluation of the learning units could be adapted in different situations; these possible new methods have been - or will be - communicated by the teachers to the students.

5 credits	30.0 h + 15.0 h	Q2

Teacher(s)	Delcorte Arnaud ;Nysten Bernard ;			
Language :	English			
Place of the course	Louvain-la-Neuve			
Main themes	<ul> <li>Introduction to Surface Science;</li> <li>Electron spectrometries (LEED, AES, XPS) and Ion spectrometries (ISS, RBS, SIMS);</li> <li>Near field microscopies (STM, AFM).</li> </ul>			
Aims	<ul> <li>Introduction to Surface Science;</li> <li>Electron spectrometries (LEED, AES, XPS) and Ion spectrometries (ISS, RBS, SIMS);</li> </ul>			

Evaluation methods	Due to the COVID-19 crisis, the information in this section is particularly likely to change. Oral examination regarding the competencies that have to be acquired				
Teaching methods	Due to the COVID-19 crisis, the information in this section is particularly likely to change. Electron and ionic spectroscopies:				
	9 lectures of 2h each (including a 1 hour general introduction on surface science) and 2 laboratories illustrating selected techniques (instrumental aspects + data interpretation; reports asked to the students).				
	Scanning probe microscopies (SPM): 5 lectures of 2h each and 2 laboratories illustrating two SPM techniques. For the laboratories, students of 2nd Master are encouraged to bring their own samples.				
Content	1. Introduction ro surface science				
	2. Electronic and ionic spectroscopies				
	2.1. Electron diffraction (LEED/RHEED)				
	2.2. X-ray photoelectron spectroscopy (XPS/ESCA)				
	2.3. Auger electron spectroscopy/microscopy (AES/SAM)				
	2.4. Ion scattering spectroscopy (ISS)				
	2.5. Secondary ion mass spectrometry (SIMS)				
	3. Scanning probe microscopies				
	3.1. Scanning tunnelling microscopy and spectroscopy				
	3.2. Atomic force microscopies				
	3.2.1. Contact mode microscopies : C-AFM, LFM, FMM, CS-AFM, PFM,				
	3.2.2. Resonant mode microscopies : AM-AFM, FM-AFM, MFM, EFM, KPFM,				
	3.2.3. Instrumental aspects : scanner, probes, artifacts,				
Inline resources	https://moodleucl.uclouvain.be/course/view.php?id=8985				
Bibliography	Spectroscopies électroniques et ioniques :				
Dibilography	Dias présentées aux cours, disponibles sur Moodle				
	Notes d'application des fabricants d'équipement				
	Liste d'ouvrages de référence, que les étudiants peuvent trouver à la bibliothèque / au laboratoire				
	Microscopies à sonde locale (SPM) :				
	<ul> <li>Notes de cours évolutives (syllabus) disponible au SICI et sur Moodle</li> <li>Dias présentées aux cours, prospectus et notes d'application de fabricants d'équipement disponibles sur Moodle</li> </ul>				
Other infos	It is highly recommended to have attended the LMAPR2011 « Methods of Physical and Chemical Analysis » course or an equivalent.				
Faculty or entity in	FYKI				
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Programmes containing this learning unit (UE)						
Program title	Acronym	Credits	Prerequisite	Aims		
Master [120] in Biomedical Engineering	GBIO2M	5		٩		
Master [120] in Physical Engineering	FYAP2M	5		٩		
Master [120] in Chemical and Materials Engineering	KIMA2M	5		٩		